

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit	Patrick J. Assouad	
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	B	US-2004/0130297 a1	07-2004	Baeuerlein et al.	320/137
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NON-PATENT DOCUMENTS

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	V	Plow et al., "Float Current Monitoring and Evaluation", IEEE, 2000.
	W	Taniguchi et al., "A Method for Identifying the Full Charging Point and the Degree of Deterioration of Lead-Acid Batteries", IEEE, 2000.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.